



Based on Form PTO-1449  
(3/90)

LIST OF REFERENCES CITED BY APPLICANT  
(Use several sheets if necessary)

ATTY. DOCKET NO.  
450100-03368

SERIAL NO.  
09/955,339

APPLICANT  
Katsuo NIRE

FILING DATE  
September 17, 2001

GROUP  
2661

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
Alie	AA	5 410 343	04/25/95	Coddington et al.			
Alie	AB	5 920 701	07/06/99	Miller et al.			
	AC						
	AD						
	AE						
	AF						
	AG						

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SEP 04 2003

Technology Center 2600

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
Alie	AH	EP 0 537 814	04/21/93	Europe			
Alie	AI	WO 95 34168	12/14/95	PCT			
	AJ						
	AK						
	AL						

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

Alie	AM	VAZQUEZ-CORTIZO D ET AL: "FS-aloha, a collision resolution algorithm with Qos support for the contention channel in multiservices wireless Lan" GLOBAL COMMUNICATIONS CONFERENCE (GLOBECOM 99), vol. 5, 5 December 1999 (1999-12-05), pages 2773-2777, XP010373453
Alie	AN	"WIRELESS MEDIUM ACCESS CONTROL (MAC) AND PHYSICAL (PHY) SPECIFICATIONS" IEEE STANDARD 802.11-1997, XX, XX, 1997, pages 71-99, XP002927753
Alie	AO	GANG WU ET AL: "WINMAC: a novel transmission protocol for infostations" VEHICULAR TECHNOLOGY CONFERENCE, 1999 IEEE 49TH HOUSTON, TX, USA 16-20 MAY 1999, PISCATAWAY, NJ, USA, IEEE, US, 16 May 1999 (1999-05-16), pages 1340-1344, XP010342188, ISBN: 0-7803-5565-2
Alie	AP	TRUMAN T E ET AL: "THE INFOPAD MULTIMEDIA TERMINAL: A PORTABLE DEVICE FOR WIRELESS INFORMATION ACCESS" IEEE TRANSACTIONS ON COMPUTERS, IEEE INC, NEW YORK, US, vol. 47, no. 10, 1 October 1998 (1998-10-01), pages 1073-1087, XP000781992, ISSN: 0018-9340

EXAMINER

*Anders*

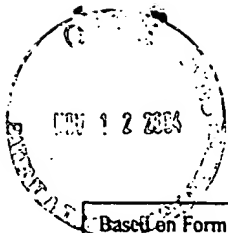
DATE CONSIDERED

April 12, 2005

\* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



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				FILING DATE September 17, 2001		GROUP 2661	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>Hee</i>	AA	5 917 810	06/29/99	De Bot			
	AB						
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FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
	AL						
	AM						
	AN						
	AO						
	AP						
OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)							
	AQ						
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	AS						
EXAMINER <i>Inde</i>				DATE CONSIDERED <i>Apr 12, 2005</i>			
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Sheet 1 of 2

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	APPLICANT Katsuo NIRE	
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U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
Hee	AA	5 933 141	08/03/99	Smith			
Hee	AB	6 417 869	07/09/02	Do			
Hee	AC	5 949 432	09/07/99	Gough et al.			
Hee	AD	5 896 131	04/20/99	Alexander			
Hee	AE	6 670 970	12/30/03	Bonura et al.			
Hee	AF	6 097 441	08/01/00	Allport			
Hee	AG	6 263 503	07/17/01	Margulis			
Hee	AH	6 396 523	05/28/02	Segal et al.			
Hee	AI	6 469 633	10/22/02	Wachter			
Hee	AJ	5 410 326	04/25/95	Goldstein			
Hee	AK	6 028 600	02/22/00	Rosin et al.			
Hee	AL	6 037 998	03/14/00	Usui et al.			
Hee	AM	5 467 341	11/14/95	Matsukane et al.			
Hee	AN	5 101 499	03/31/92	Streck et al.			
Hee	AO	5 802 467	09/01/98	Salazar et al.			
Hee	AP	6 012 088	01/04/00	Li et al.			
Hee	AQ	5 862 339	01/19/99	Bonnaure et al.			

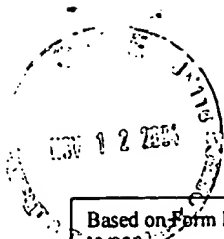
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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
Hee	AR	WO 99 34599	07/08/99	PCT			
Hee	AS	EP 0 838 945	04/29/98	Europe			
Hee	AT	EP 1 001 627	05/17/00	Europe			
Hee	AU	EP 0 617 556	09/28/94	Europe			
Hee	AV	EP 0 967 797	12/29/99	Europe			

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Sheet 2 of 2

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	AA						
FOREIGN PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
<i>Free</i>	AB	GB 2 343 334	05/03/00	U.K.			
<i>Free</i>	AC	CN 1249644	04/05/00	China			Abstract
<i>Free</i>	AD	EP 0 942 572	09/15/99	Europe			
<i>Free</i>	AE	WO 01 35551	05/17/01	PCT			
<i>Free</i>	AF	EP 1 011 257	06/21/00	Europe			
<i>Free</i>	AG	EP 0 477 754	04/01/92	Europe			
<i>Free</i>	AH	DE 200 00 450	03/09/00	Germany			Abstract
<i>Free</i>	AI	DE 196 28 540	01/22/98	Germany			Abstract
<i>Free</i>	AJ	EP 0 848 560	06/17/98	Europe			
<i>Free</i>	AK	WO 98 59282	12/30/98	PCT			
<i>Free</i>	AL	WO 01 35585	05/17/01	PCT			
<i>Free</i>	AM	EP 0 793 170	09/03/97	Europe			
<i>Free</i>	AN	WO 00 14919	03/16/00	PCT			
OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)							
<i>Free</i>	AO	PATENT ABSTRACTS OF JAPAN vol. 1998, no. 14, 31 December 1998 (1998-12-31) & JP 10 257401 A (ACCESS:KK) 25 September 1998 (1998-09-25)					
<i>Free</i>	AP	PATENT ABSTRACTS OF JAPAN, 2001-177478 dated June 29, 2001					
EXAMINER  <i>Andrew</i>				DATE CONSIDERED  <i>April 12, 2005</i>			
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